



A UVM Reactive Testbench for Jitter Tolerance Measurement of High-Speed Wireline Receivers

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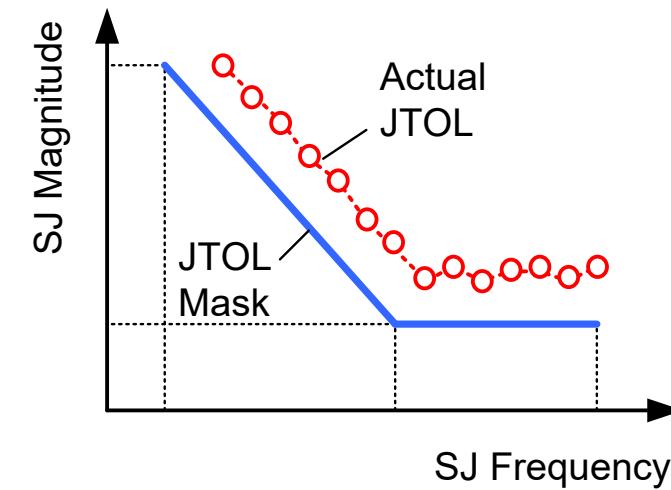
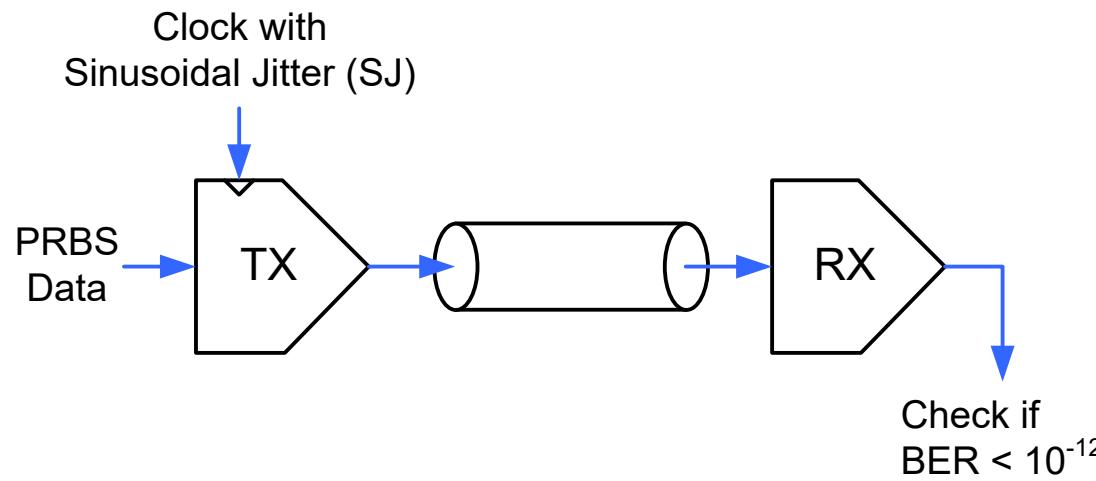
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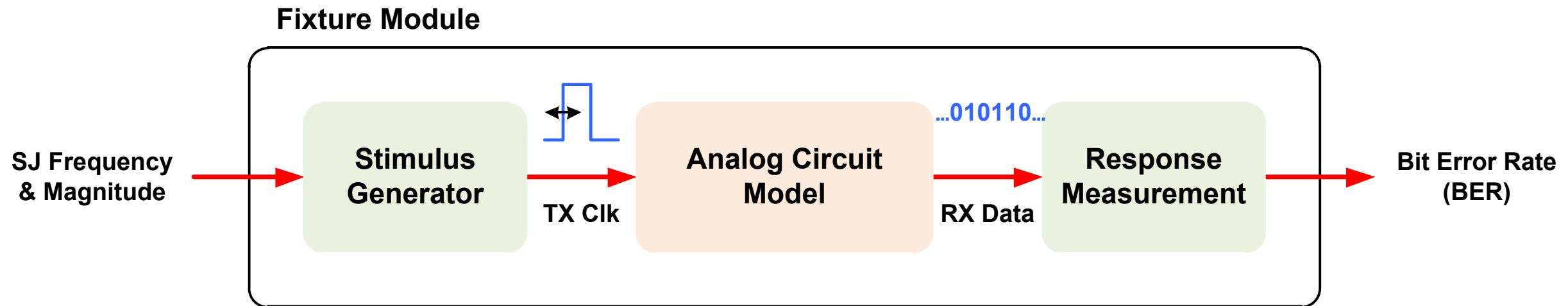
Jitter Tolerance (JTOL) of High-Speed Receivers

- Jitter tolerance (JTOL) test measures the resilience of a high-speed wireline receiver by finding the maximum magnitude of an additional sinusoidal jitter (SJ) that can be tolerated for a target BER (e.g. 10^{-12})
- This work presents a UVM testbench performing such an iterative search



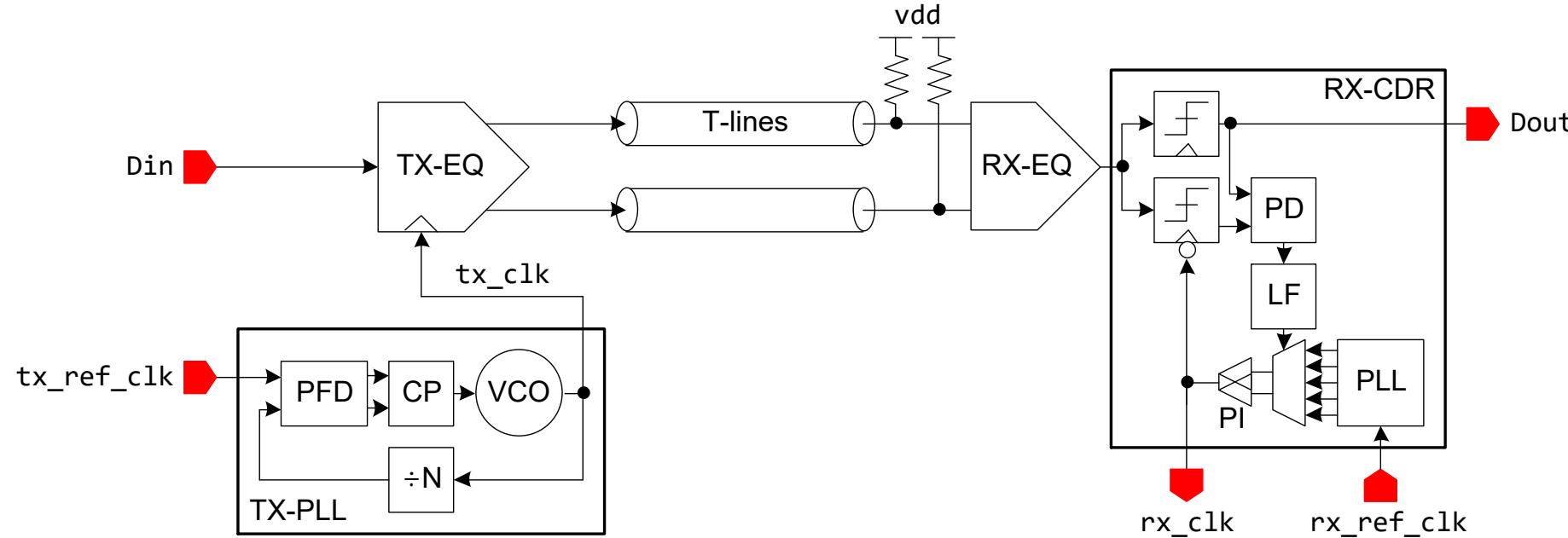
Extending UVM to Analog/Mixed-Signal Verification

- UVM testbenches for AMS circuits can be built with standard components if we use a well-defined ***fixture module*** enclosing these elements:
 - AMS device under verification (DUV) modeled in SystemVerilog
 - Analog instrumentations for generating stimuli and measuring responses



Modeling a High-Speed Wireline Transceiver

- Requires capabilities of simulating analog pulses propagating through a lossy channel, expressing precise timing of PLL & CDR, and modeling analog circuits directly as a network of circuit elements in SystemVerilog



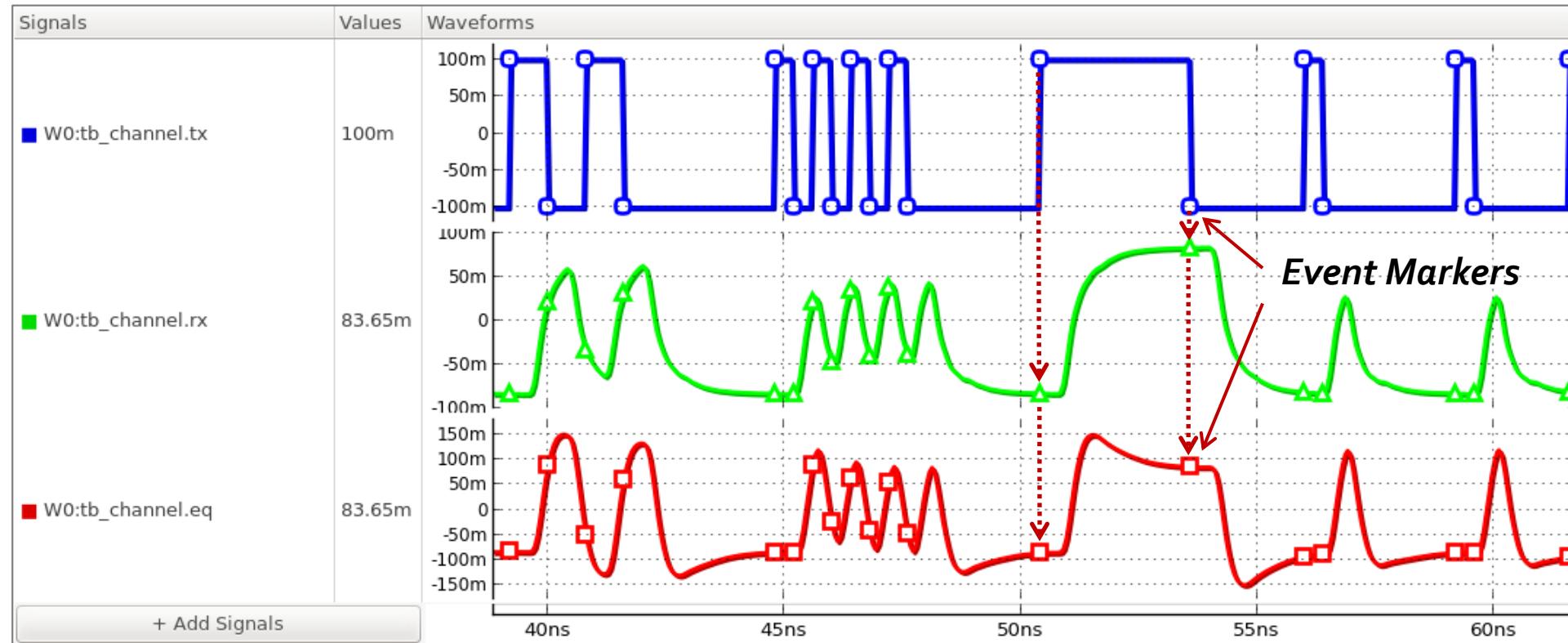
XMODEL Enables Analog in SystemVerilog/UVM

- XMODEL is a plug-in extension enabling *fast and accurate analog/mixed-signal* simulation in *SystemVerilog*
 - *Event-driven*: delivering 10~100x faster speed than Real-Number Model (RNM)
 - *Analog*: supporting both functional and circuit-level models
 - *SystemVerilog*: fully compliant with SystemVerilog-based flows (e.g. UVM)



Event-Driven Simulation of XMODEL

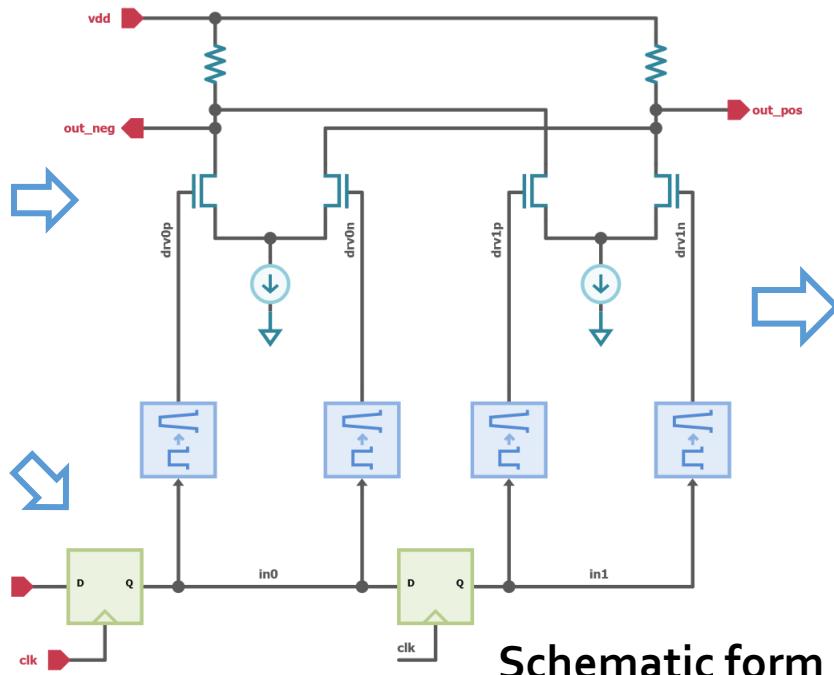
- Ideal for simulating data pulses through the lossy channel and equalizer



Equalizing Transmitter Model Example

- AMS models are composed by putting together the *XMODEL* primitives

Can describe circuit directly as a network of circuit primitives



Timing accuracy of digital pulses is not limited by timestep

Source form

```

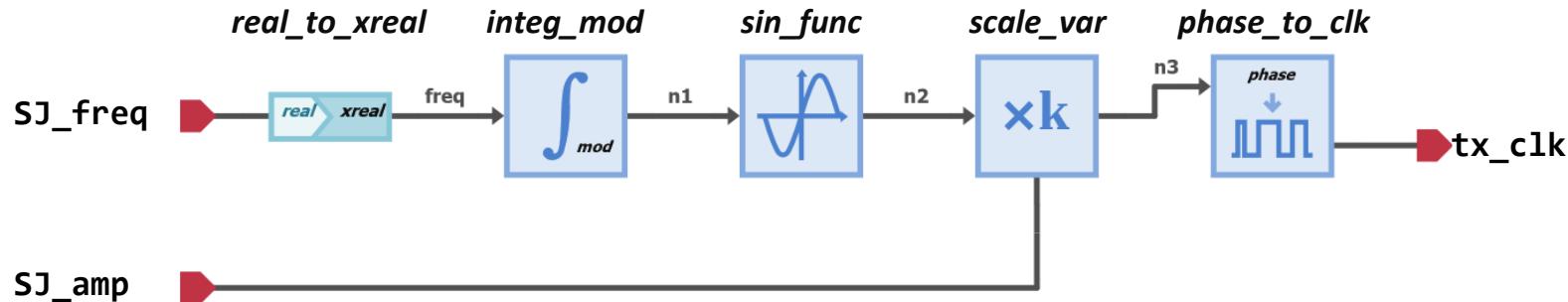
module tx_eq (...);
xreal drv0p, drv0n, drv1p, drv1n;
xreal tail0, tail1;
xbit in0, in1;

isource #( .mode("dc"), .dc(0.00875))
I0 (.neg(`ground), .pos(tail0), .in(`ground));
isource #( .mode("dc"), .dc(0.00125))
I1 (.neg(`ground), .pos(tail1), .in(`ground));
nmosfet #( .W(2e-05), .L(4e-08), .Kp(2e-05), .Vth(0.5))
M0 (.g(drv0p), .d(out_neg), .b(`ground), .s(tail0));
nmosfet #( .W(2e-05), .L(4e-08), .Kp(2e-05), .Vth(0.5))
M1 (.g(drv0n), .d(out_pos), .b(`ground), .s(tail0));
nmosfet #( .W(2e-05), .L(4e-08), .Kp(2e-05), .Vth(0.5))
M2 (.g(drv1p), .d(out_neg), .b(`ground), .s(tail1));
nmosfet #( .W(2e-05), .L(4e-08), .Kp(2e-05), .Vth(0.5))
M3 (.g(drv1n), .d(out_pos), .b(`ground), .s(tail1));
resistor #( .R(50)) R0 (.neg(out_pos), .pos(vdd));
resistor #( .R(50)) R1 (.neg(out_neg), .pos(vdd));
transition #( .value0(0.0), .value1(1.0)) XP0 (.out(drv0p), .in(in0));
transition #( .value0(1.0), .value1(0.0)) XP1 (.out(drv0n), .in(in0));
transition #( .value0(1.0), .value1(0.0)) XP2 (.out(drv1p), .in(in1));
transition #( .value0(0.0), .value1(1.0)) XP3 (.out(drv1n), .in(in1));
dff_xbit XP4 (.clk(clk), .d(in), .q(in0));
dff_xbit XP5 (.clk(clk), .d(in0), .q(in1));
endmodule // tx_eq

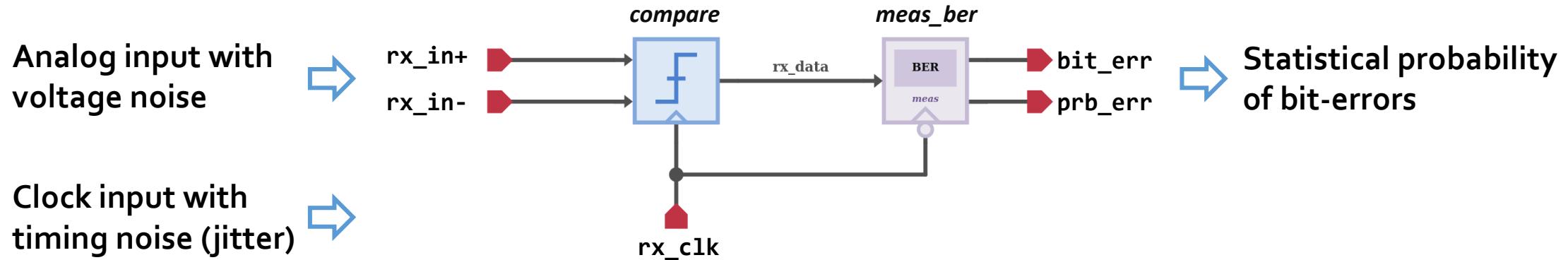
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Fixture Module with Analog Instrumentations

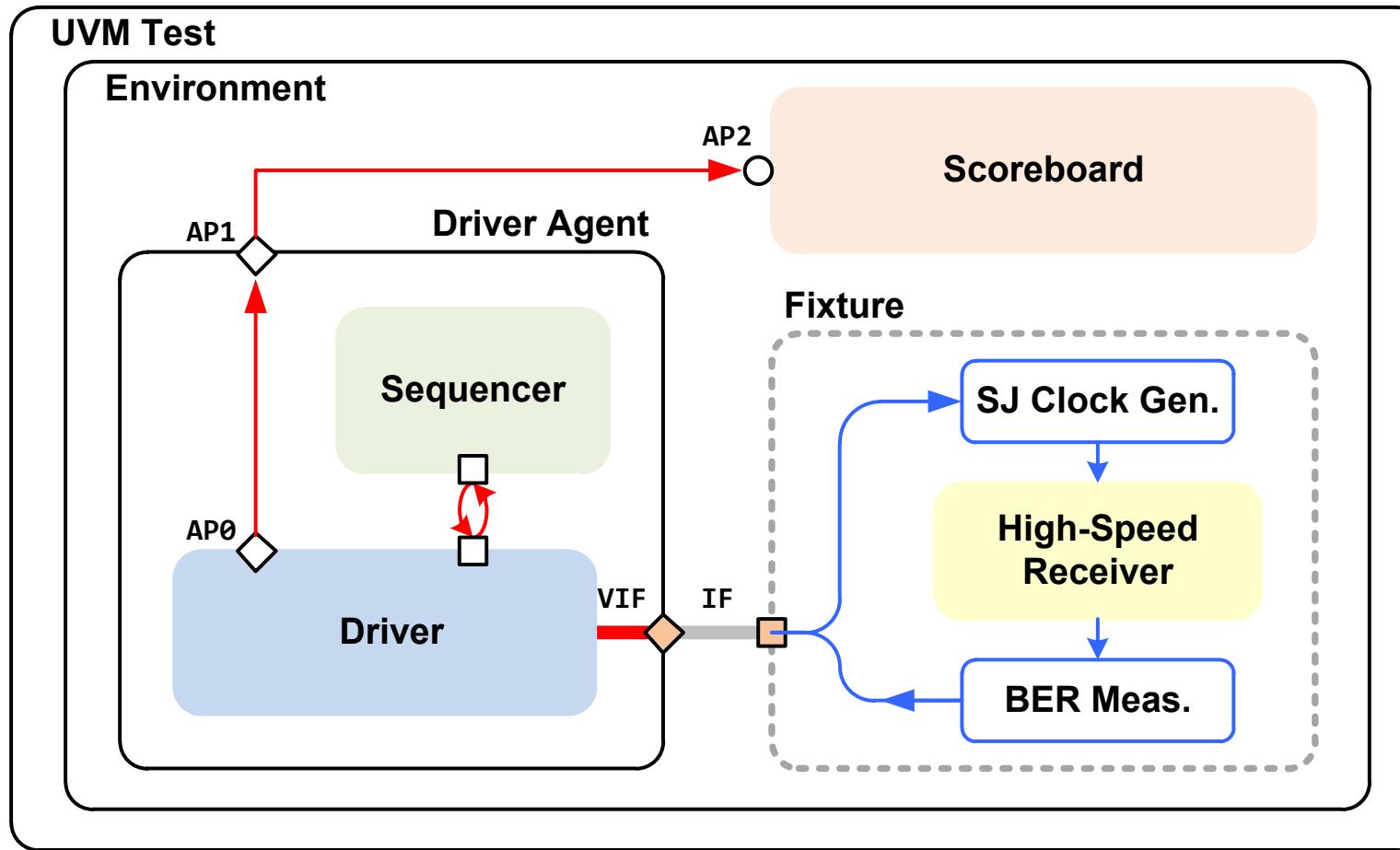
- Generating a clock with SJ from the frequency & amplitude inputs:



- Measuring the BER of the received data using statistical simulation:



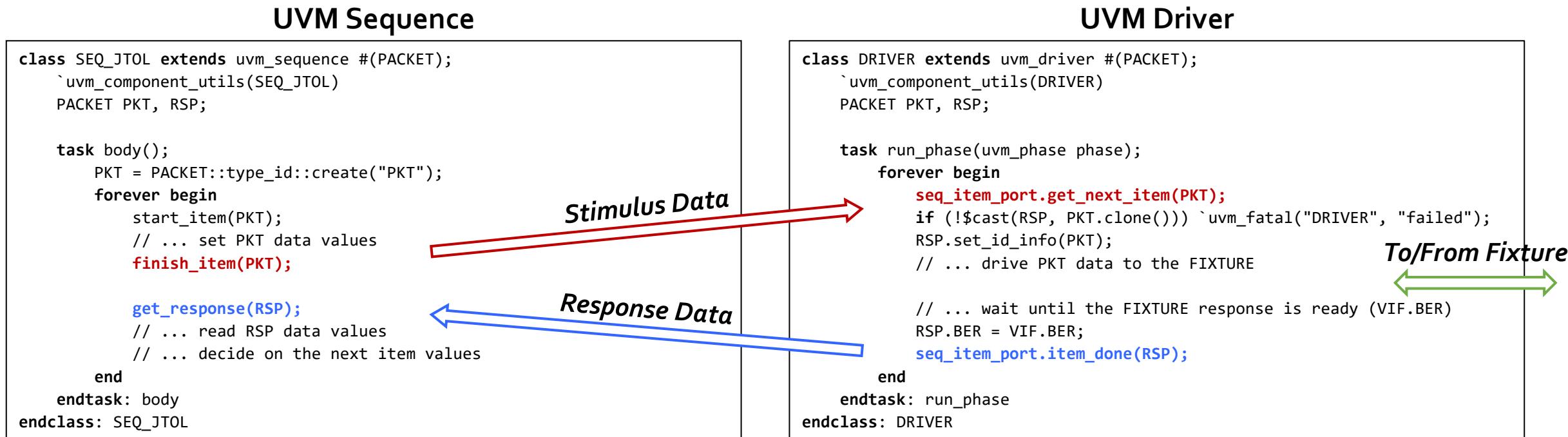
UVM Testbench for JTOL Measurement



- The rest of testbench can be built using the standard UVM components
 - Sequencer
 - Driver
 - Scoreboard

UVM Reactive Stimulus Technique

- A technique to reactively generate the next sequence item based on the result of the previous sequence items [Cummings, et al., 2020]



Search Algorithms for JTOL Measurement

```

class SEQ_JTOL extends uvm_sequence #(PACKET);
  task body();
    // ... details omitted for brevity
    flag = 0;

    // phase 1: linear search to find the first failing point
    while (1) begin
      start_item(PKT); finish_item(PKT); get_response(RSP);
      if (RSP.BER < RSP.BER_tol) begin
        mag_min = PKT.SJ_mag;
        PKT.SJ_mag += mag_inc;
        if (flag == -1) break; else flag = 1;
      end
      else begin
        mag_max = PKT.SJ_mag;
        PKT.SJ_mag -= mag_inc;
        if (flag == 1) break; else flag = -1;
      end
    end

    // phase 2: binary search to find the pass/fail boundary
    while (mag_max/mag_min > 1.05) begin
      PKT.SJ_mag = $sqrt(mag_max * mag_min);
      start_item(PKT); finish_item(PKT); get_response(RSP);
      if (RSP.BER < RSP.BER_tol) mag_min = PKT.SJ_mag;
      else mag_max = PKT.SJ_mag;
    end
  endtask: body
endclass: SEQ_JTOL

```

- Using the reactive stimulus technique, the max. SJ magnitude with $\text{BER} < 10^{-12}$ is found in two steps:
 - Linear search to identify an interval containing the BER pass/fail boundary
 - Binary search to refine the boundary

UVM Scoreboard

```
class SCOREBOARD extends uvm_scoreboard;
  `uvm_component_utils(SCOREBOARD)
  SCORECARD SCD;
  PACKET PKT;
  uvm_analysis_export #(PACKET) AP2;
  uvm_tlm_analysis_fifo #(PACKET) FIFO;

  task run_phase(uvm_phase phase);
    int N;
    forever begin
      FIFO.get(PKT);
      N = PKT.tag;
      if (SCD.DATA.exists(N)) begin
        if (PKT.BER < PKT.BER_tol && SCD.DATA[N].mag < PKT.SJ_mag)
          SCD.DATA[N].mag = PKT.SJ_mag;
      end
      else begin
        SCD.DATA[N].freq = PKT.SJ_freq;
        SCD.DATA[N].mag = (PKT.BER < PKT.BER_tol) ? PKT.SJ_mag : 0.0;
      end
      SCD.num_trials++;
    end
  endtask: run_phase

endclass: SCOREBOARD
```

- Driver broadcasts the BER result of each trial to the scoreboard
- Scoreboard keeps the record of the max. SJ magnitude with $\text{BER} < 10^{-12}$ for each SJ frequency

UVM Simulation Log

- Simulation takes 41 min. running 10^6 BER trials for 20 SJ frequencies

```

UVM_INFO @ 2210.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 20 SJ freq=5.00000e+09 Hz, mag=5.00000e-01 UIpp --> BER=6.033595e-04
UVM_INFO @ 4411.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 20 SJ freq=5.00000e+09 Hz, mag=4.00000e-01 UIpp --> BER=4.253071e-06
UVM_INFO @ 6612.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 20 SJ freq=5.00000e+09 Hz, mag=3.00000e-01 UIpp --> BER=4.559507e-09
UVM_INFO @ 8813.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 20 SJ freq=5.00000e+09 Hz, mag=2.00000e-01 UIpp --> BER=4.824476e-13
UVM_INFO @ 11014.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 20 SJ freq=5.00000e+09 Hz, mag=2.449490e-01 UIpp --> BER=3.271928e-11
UVM_INFO @ 13215.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 20 SJ freq=5.00000e+09 Hz, mag=2.213364e-01 UIpp --> BER=3.781672e-12
UVM_INFO @ 15416.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 20 SJ freq=5.00000e+09 Hz, mag=2.103979e-01 UIpp --> BER=1.263946e-12
UVM_INFO @ 17617.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 20 SJ freq=5.00000e+09 Hz, mag=2.051331e-01 UIpp --> BER=7.470467e-13
UVM_INFO @ 19818.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 19 SJ freq=3.475964e+09 Hz, mag=2.051331e-01 UIpp --> BER=2.923724e-15
UVM_INFO @ 22019.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 19 SJ freq=3.475964e+09 Hz, mag=2.461597e-01 UIpp --> BER=8.445417e-14
UVM_INFO @ 24220.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 19 SJ freq=3.475964e+09 Hz, mag=2.871863e-01 UIpp --> BER=2.007209e-12
UVM_INFO @ 26421.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 19 SJ freq=3.475964e+09 Hz, mag=2.658829e-01 UIpp --> BER=4.560037e-13
UVM_INFO @ 28622.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 19 SJ freq=3.475964e+09 Hz, mag=2.763294e-01 UIpp --> BER=7.860811e-13
(...)
```

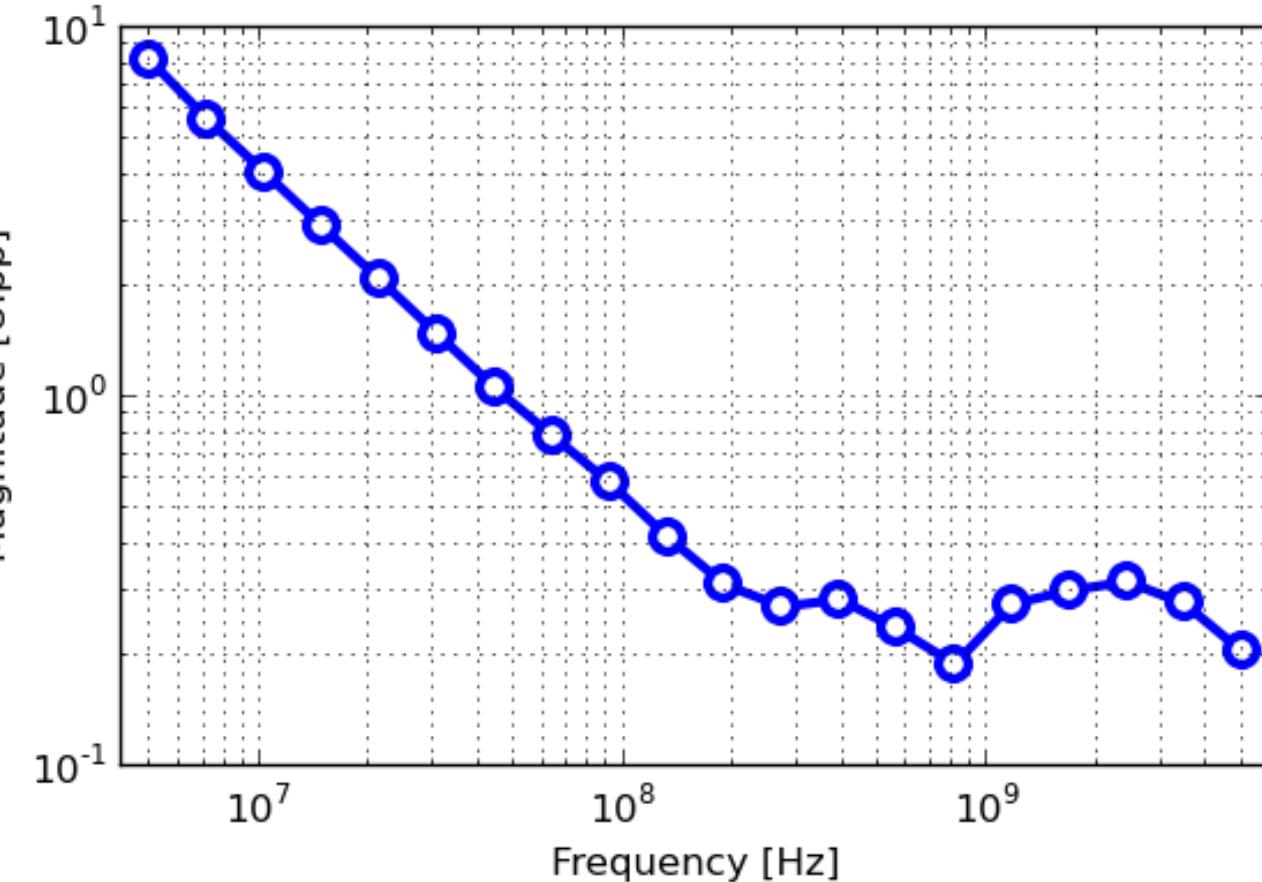
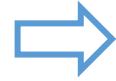
```

(...) 
UVM_INFO @ 206903.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 3 SJ freq=1.034569e+07 Hz, mag=4.320903e+00 UIpp --> BER=9.844018e-09
UVM_INFO @ 209104.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 3 SJ freq=1.034569e+07 Hz, mag=4.179040e+00 UIpp --> BER=2.617306e-11
UVM_INFO @ 211305.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 2 SJ freq=7.192249e+06 Hz, mag=4.179040e+00 UIpp --> BER=2.324675e-19
UVM_INFO @ 213506.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 2 SJ freq=7.192249e+06 Hz, mag=5.014848e+00 UIpp --> BER=1.745598e-17
UVM_INFO @ 215707.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 2 SJ freq=7.192249e+06 Hz, mag=5.850657e+00 UIpp --> BER=1.286969e-12
UVM_INFO @ 217908.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 2 SJ freq=7.192249e+06 Hz, mag=5.416655e+00 UIpp --> BER=3.667517e-16
UVM_INFO @ 220109.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 2 SJ freq=7.192249e+06 Hz, mag=5.629475e+00 UIpp --> BER=4.189074e-15
UVM_INFO @ 222310.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 1 SJ freq=5.00000e+06 Hz, mag=5.629475e+00 UIpp --> BER=1.387735e-20
UVM_INFO @ 224511.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 1 SJ freq=5.00000e+06 Hz, mag=6.755370e+00 UIpp --> BER=4.093819e-19
UVM_INFO @ 226712.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 1 SJ freq=5.00000e+06 Hz, mag=7.881265e+00 UIpp --> BER=1.972978e-15
UVM_INFO @ 228913.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 1 SJ freq=5.00000e+06 Hz, mag=9.007160e+00 UIpp --> BER=2.232116e-03
UVM_INFO @ 231114.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 1 SJ freq=5.00000e+06 Hz, mag=8.425427e+00 UIpp --> BER=2.148739e-11
UVM_INFO @ 233315.000ns: uvm_test_top.E.AGNT.DRV [RUN]
| # 1 SJ freq=5.00000e+06 Hz, mag=8.148805e+00 UIpp --> BER=8.002244e-15
```

Simulated Jitter Tolerance (JTOL) Results

JITTER TOLERANCE (JTOL)		
INDEX	FREQUENCY(Hz)	MAGNITUDE(UIpp)
1	5.0000e+06	8.1488
2	7.1922e+06	5.6295
3	1.0346e+07	4.0418
4	1.4882e+07	2.8870
5	2.1407e+07	2.0728
6	3.0792e+07	1.4806
7	4.4293e+07	1.0576
8	6.3714e+07	0.7851
9	9.1649e+07	0.5858
10	1.3183e+08	0.4184
11	1.8963e+08	0.3106
12	2.7278e+08	0.2709
13	3.9238e+08	0.2834
14	5.6442e+08	0.2362
15	8.1189e+08	0.1894
16	1.1679e+09	0.2756
17	1.6799e+09	0.2996
18	2.4165e+09	0.3168
19	3.4760e+09	0.2763
20	5.0000e+09	0.2051

TOTAL NUMBER OF TRIALS: 106



Summary

- A UVM testbench for AMS circuits can be built using standard UVM components with a well-defined fixture module
- To measure the jitter tolerance of a high-speed wireline receiver:
 - The fixture module enclosing the transceiver model and its instrumentations can be composed with *XMODEL* primitives
 - Search for maximum SJ can be performed using the reactive stimulus technique
- This work was supported by Samsung Electronics, Co. Ltd. and the EDA tools were supported by IDEC and Scientific Analog, Inc.